DATA SHEET

BT151U series C
Thyristors

Product specification

August 2018

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Thyristors | BT151U series C

GENERAL DESCRIPTION

Passivated thyristors in a plastic envelope, intended for use in applications requiring high bidirectional blocking voltage capability and high thermal cycling performance. Typical applications include motor control, industrial and domestic lighting, heating and static switching.

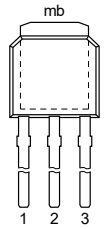
QUICK REFERENCE DATA

SYMBOL	PARAMETER	MAX.	MAX.	MAX.	UNIT
	BT151U-	**500C**	**650C**	**800C**	
V_{DRM}, V_{RRM}	Repetitive peak off-state voltages	500	650	800	V
$I_{T(AV)}$	Average on-state current	7.5	7.5	7.5	A
$I_{T(RMS)}$	RMS on-state current	12	12	12	A
I_{TSM}	Non-repetitive peak on-state current	100	100	100	A

PINNING - SOT533, (I-PAK)

PIN NUMBER	DESCRIPTION
1	cathode
2	anode
3	gate
tab	anode

PIN CONFIGURATION



IPAK (SOT533)

SYMBOL

sym037

LIMITING VALUES

Limiting values in accordance with the Absolute Maximum System (IEC 60134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.			UNIT
				-500C	**-650C**	**-800C**	
V_{DRM}, V_{RRM}	Repetitive peak off-state voltages		-	500[1]	650[1]	800	V
$I_{T(AV)}$	Average on-state current	half sine wave; $T_{mb} \leq 104$ ˚C	-	7.5			A
$I_{T(RMS)}$	RMS on-state current	all conduction angles	-	12			A
I_{TSM}	Non-repetitive peak on-state current	half sine wave; $T_j = 25$ ˚C prior to surge					
		t = 10 ms	-	100			A
		t = 8.3 ms	-	110			A
I^2t	I^2t for fusing	t = 10 ms	-	50			A^2s
dI_T/dt	Repetitive rate of rise of on-state current after triggering	I_{TM} = 20 A; I_G = 50 mA; dI_G/dt = 50 mA/µs	-	50			A/µs
I_{GM}	Peak gate current		-	2			A
V_{RGM}	Peak reverse gate voltage		-	5			V
P_{GM}	Peak gate power		-	5			W
$P_{G(AV)}$	Average gate power	over any 20 ms period	-	0.5			W
T_{stg}	Storage temperature		-40	150			˚C
T_j	Junction temperature		-	125			˚C

1 Although not recommended, off-state voltages up to 800V may be applied without damage, but the thyristor may switch to the on-state. The rate of rise of current should not exceed 15 A/µs.

THERMAL RESISTANCES

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$R_{th\ j\text{-}mb}$	Thermal resistance junction to mounting base		-	-	1.3	K/W
						K/W
$R_{th\ j\text{-}a}$	Thermal resistance junction to ambient	in free air	-	70	-	K/W

STATIC CHARACTERISTICS

T_j = 25 ˚C unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
I_{GT}	Gate trigger current	V_D = 12 V; I_T = 0.1 A	-	2	15	mA
I_L	Latching current	V_D = 12 V; I_{GT} = 0.1 A	-	10	40	mA
I_H	Holding current	V_D = 12 V; I_{GT} = 0.1 A	-	7	20	mA
V_T	On-state voltage	I_T = 23 A	-	1.44	1.75	V
V_{GT}	Gate trigger voltage	V_D = 12 V; I_T = 0.1 A	-	0.6	1.5	V
		$V_D = V_{DRM(max)}$; I_T = 0.1 A; T_j = 125 ˚C	0.25	0.4	-	V
I_D, I_R	Off-state leakage current	$V_D = V_{DRM(max)}$; $V_R = V_{RRM(max)}$; T_j = 125 ˚C	-	0.1	0.5	mA

DYNAMIC CHARACTERISTICS

T_j = 25 ˚C unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
dV_D/dt	Critical rate of rise of off-state voltage	V_{DM} = 67% $V_{DRM(max)}$; T_j = 125 ˚C; exponential waveform				
		Gate open circuit	50	130	-	V/µs
		R_{GK} = 100 Ω	200	1000	-	V/µs
t_{gt}	Gate controlled turn-on time	I_{TM} = 40 A; $V_D = V_{DRM(max)}$; I_G = 0.1 A; dI_G/dt = 5 A/µs	-	2	-	µs
t_q	Circuit commutated turn-off time	V_D = 67% $V_{DRM(max)}$; T_j = 125 ˚C; I_{TM} = 20 A; V_R = 25 V; dI_{TM}/dt = 30 A/µs; dV_D/dt = 50 V/µs; R_{GK} = 100 Ω	-	70	-	µs

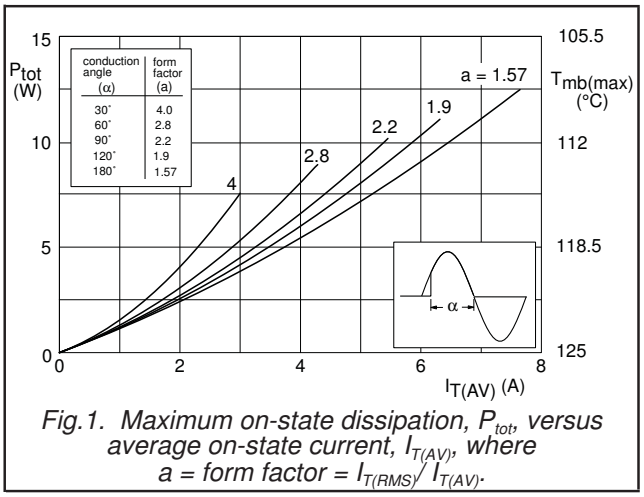


Fig.1. Maximum on-state dissipation, P_{tot}, versus average on-state current, $I_{T(AV)}$, where a = form factor = $I_{T(RMS)}/ I_{T(AV)}$.

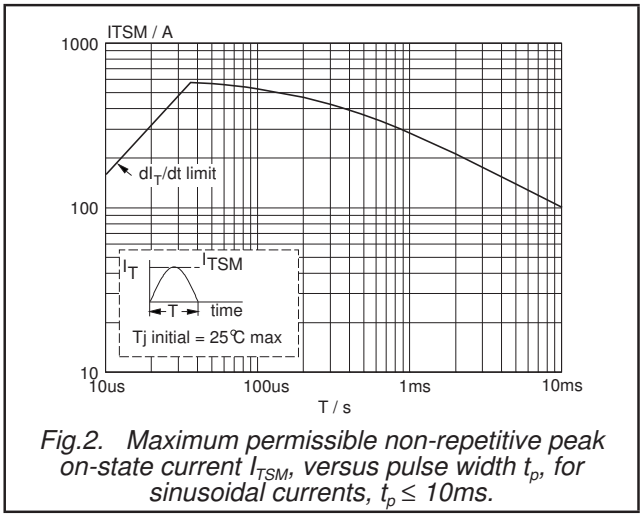


Fig.2. Maximum permissible non-repetitive peak on-state current I_{TSM}, versus pulse width t_p, for sinusoidal currents, $t_p \leq 10ms$.

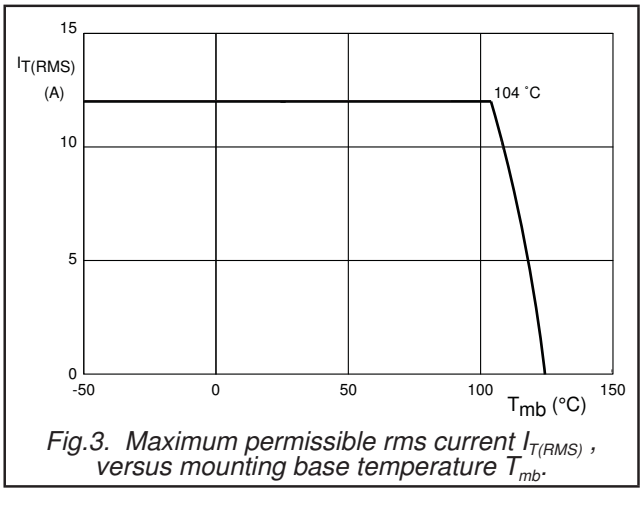


Fig.3. Maximum permissible rms current $I_{T(RMS)}$, versus mounting base temperature T_{mb}.

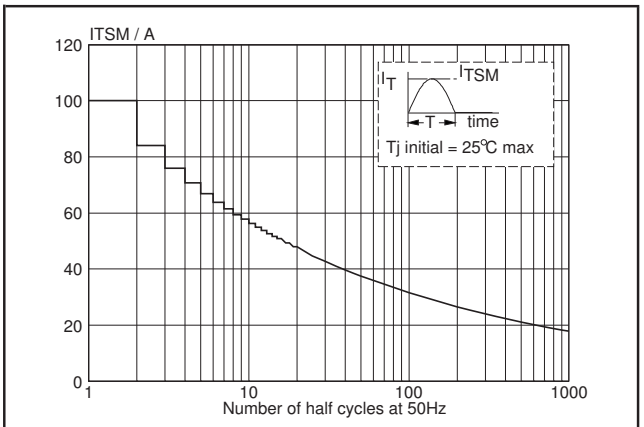


Fig.4. Maximum permissible non-repetitive peak on-state current I_{TSM}, versus number of cycles, for sinusoidal currents, f = 50 Hz.

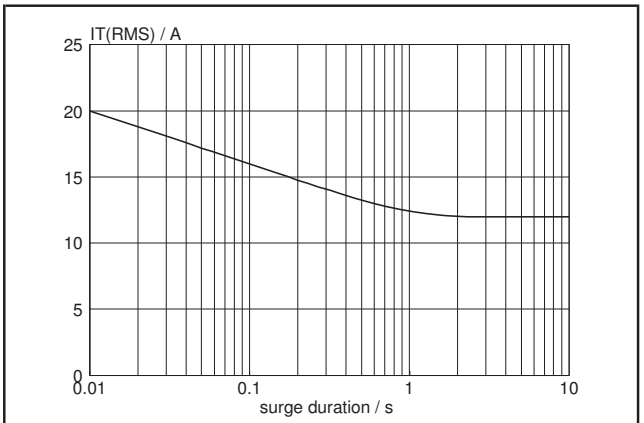


Fig.5. Maximum permissible repetitive rms on-state current $I_{T(RMS)}$, versus surge duration, for sinusoidal currents, f = 50 Hz; $T_{mb} \leq 100$ ˚C.

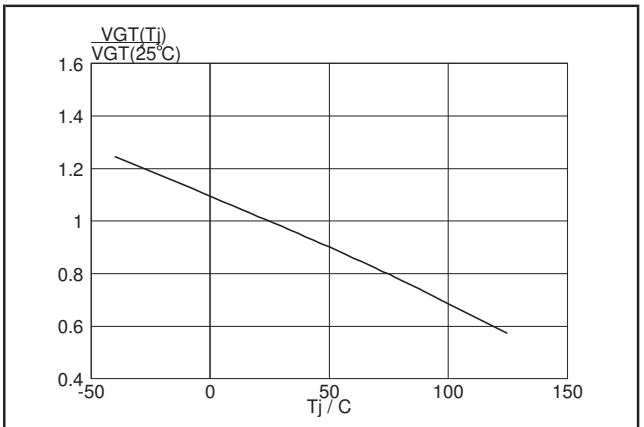


Fig.6. Normalised gate trigger voltage $V_{GT}(T_j)/ V_{GT}(25˚C)$, versus junction temperature T_j.

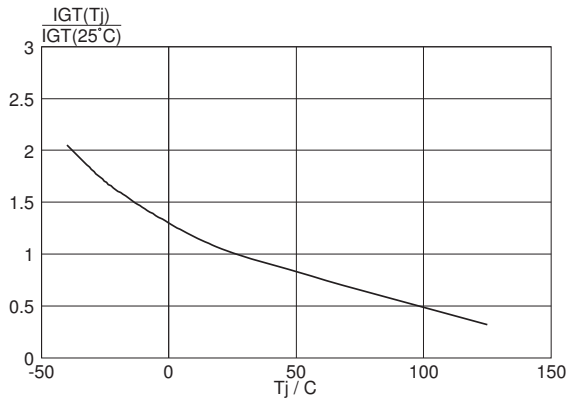


Fig.7. Normalised gate trigger current $I_{GT}(T_j)/ I_{GT}(25˚C)$, versus junction temperature T_j.

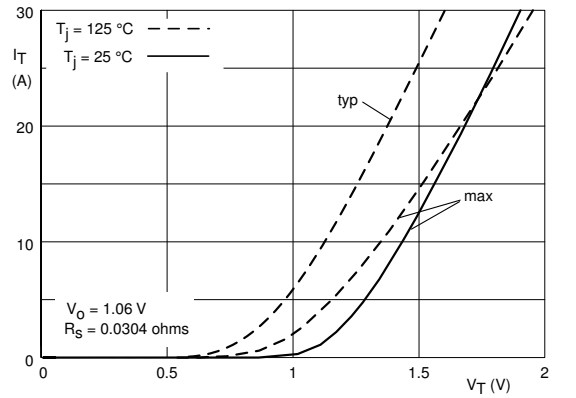


Fig.10. Typical and maximum on-state characteristic.

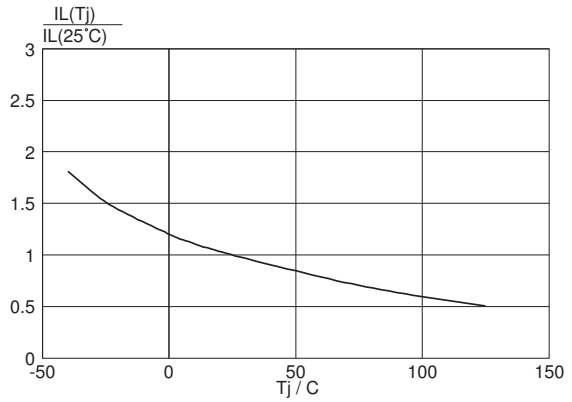


Fig.8. Normalised latching current $I_L(T_j)/ I_L(25˚C)$, versus junction temperature T_j.

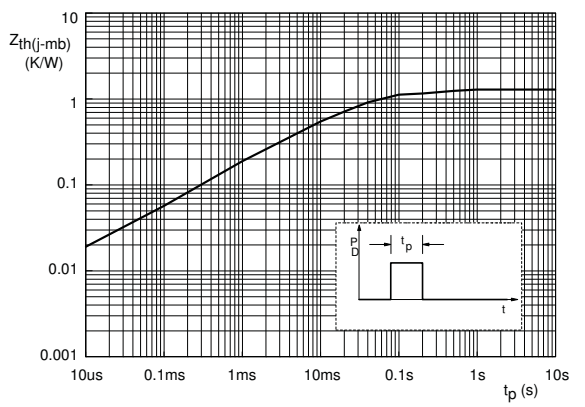


Fig.11. Transient thermal impedance $Z_{th\ j\text{-}mb}$, versus pulse width t_p.

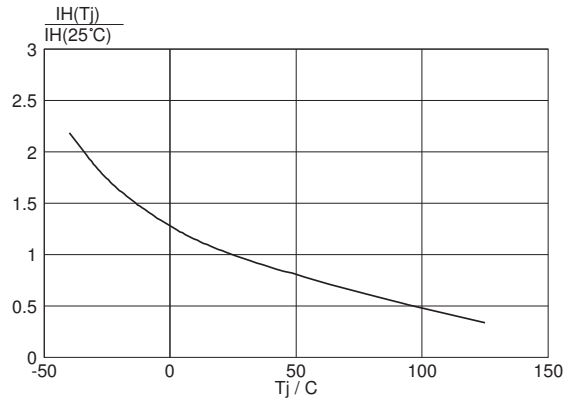


Fig.9. Normalised holding current $I_H(T_j)/ I_H(25˚C)$, versus junction temperature T_j.

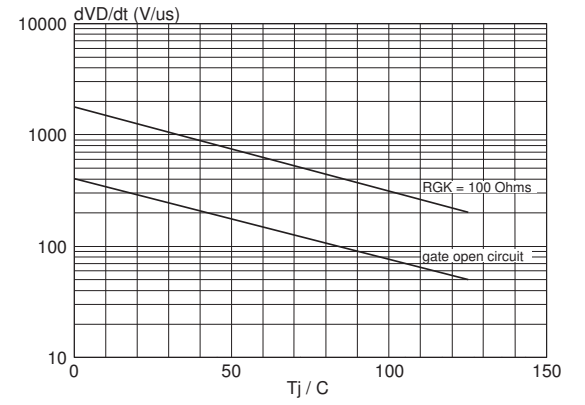
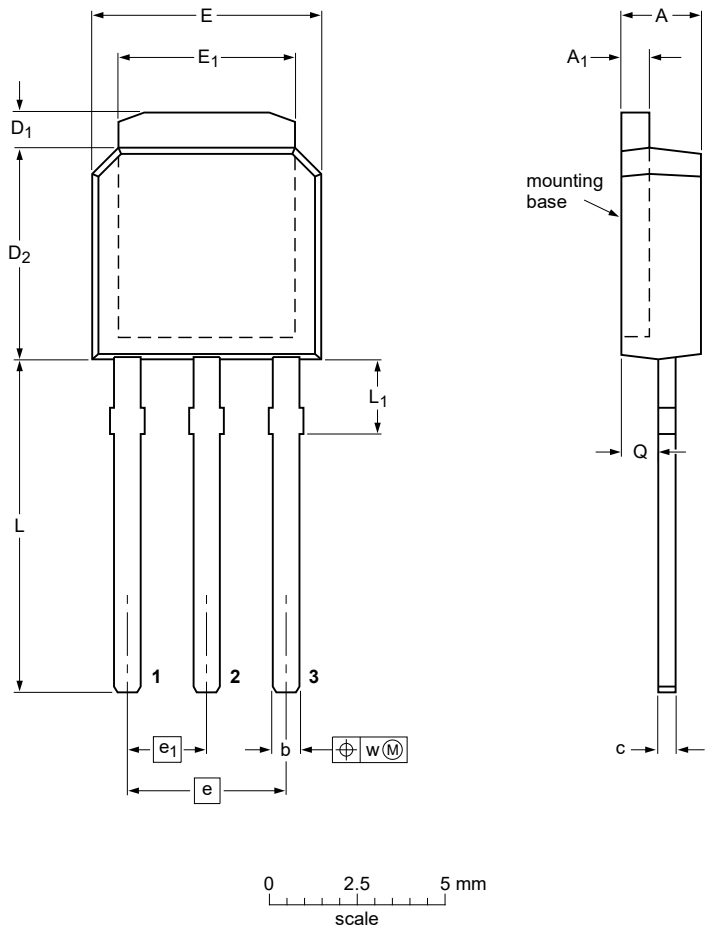


Fig.12. Typical, critical rate of rise of off-state voltage, dV_D/dt versus junction temperature T_j.

MECHANICAL DATA

Plastic single-ended package (IPAK); 3 leads (in-line) **SOT533**



DIMENSIONS (mm are the original dimensions)

UNIT	A	A_1	b	c	D_1	D_2	E	E_1	e	e_1	L	L_1(2) max	Q	w
mm	2.38 2.22	0.93 0.46	0.89 0.71	0.56 0.46	1.10 0.96	6.22 5.98	6.73 6.47	5.21 5.00	4.57 BSC(1)	2.285 BSC(1)	9.6 9.2	2.7	1.1 1.0	0.3

Notes
1. Basic spacing between centers.
2. Terminal dimensions are uncontrolled within zone L_1.

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	JEITA			
SOT533		TO-251				~~05-02-11~~ 06-02-14

Legal information

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Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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